

General Description

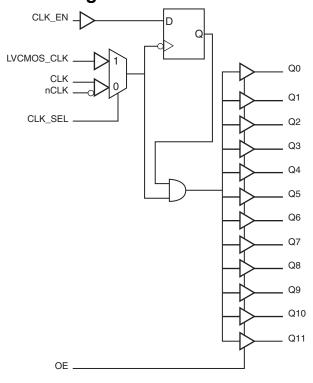
The 83948I-147 is a low skew, 1-to-12 Differential-to-LVCMOS/LVT-TL Fanout Buffer. The 83948I-147 has two selectable clock inputs. The CLK, nCLK pair can accept most standard differential input levels. The LVCMOS_CLK can accept LVCMOS or LVTTL input levels. The low impedance LVCMOS/LVTTL outputs are designed to drive 50Ω series or parallel terminated transmission lines. The effective fanout can be increased from 12 to 24 by utilizing the ability of the outputs to drive two series terminated lines.

The 83948I-147 is characterized at full 3.3V, full 2.5V or mixed 3.3V core/2.5V output operating supply modes. Guaranteed output and part-to-part skew characteristics make the 83948I-147 ideal for those clock distribution applications demanding well defined performance and repeatability.

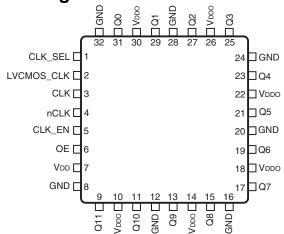
Features

- Twelve LVCMOS/LVTTL outputs
- Selectable differential CLK/nCLK or LVCMOS/LVTTL clock input
- CLK/nCLK pair can accept the following differential input levels: LVPECL, LVDS, LVHSTL, SSTL, HCSL
- LVCMOS_CLK supports the following input types: LVCMOS, LVTTL
- Output frequency: 350MHz
- Additive phase jitter, RMS: 0.14ps (typical)
- Output skew: 100ps (maximum), 3.3V±5%
- Part-to-part skew: 1ns (maximum), 3.3V±5%
- Operating supply modes:
- Core/Output 3.3V/3.3V 3.3V/2.5V 2.5V/2.5V
- -40°C to 85°C ambient operating temperature
- Lead-free (RoHS 6) packaging

Block Diagram



Pin Assignment



83948I-147 32-Lead LQFP 7mm x 7mm x 1.4mm package body Y Package Top View



Pin Descriptions and Characteristics

Table 1. Pin Descriptions

| Number | Name | Ту | ре | Description |
|--|--|--------|----------|--|
| 1 | CLK_SEL | Input | Pullup | Clock select input. When HIGH, selects LVCMOS_CLK input. When LOW, selects CLK/nCLK inputs. LVCMOS / LVTTL interface levels. |
| 2 | LVCMOS_CL K | Input | Pullup | Single-ended clock input. LVCMOS/LVTTL interface levels. |
| 3 | CLK | Input | Pullup | Non-inverting differential clock input. |
| 4 | nCLK | Input | Pulldown | Inverting differential clock input. |
| 5 | CLK_EN | Input | Pullup | Clock enable pin. LVCMOS/LVTTL interface levels. |
| 6 | OE | Input | Pullup | Output enable pin. When LOW, outputs are in an High-impedance state. when HIGH, outputs are active. LVCMOS/LVTTL interface levels. |
| 7 | V_{DD} | Power | | Power supply pin. |
| 8, 12, 16, 20, 24, 28, 32 | GND | Power | | Power supply ground. |
| 9, 11, 13, 15, 17, 19, 21, 23, 25, 27, 29, 31 | Q11, Q10, Q9, Q8, Q7, Q6, Q5, Q4, Q3, Q2, Q1, Q0 | Output | | Single-ended clock outputs. LVCMOS/LVTTL interface levels. |
| 10, 14, 18, 22, 26, 30 | V _{DDO} | Power | | Output supply pins. |

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

Table 2. Pin Characteristics

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------------------|--|-----------------|---------|---------|---------|-------|
| C _{IN} | Input Capacitance | | | 4 | | pF |
| R _{PULLUP} | Input Pullup Resistor | | | 51 | | kΩ |
| R _{PULLDOWN} | Input Pulldown Resistor | | | 51 | | kΩ |
| C _{PD} | Power Dissipation Capacitance (per output) | | | 12 | | pF |
| R _{OUT} | Output Impedance | | 5 | 7 | 12 | Ω |

Function Tables

Table 3A. Clock Select Function Table

| Control Input | Clock |
|------------------|---------------------------|
| 0 | CLK/nCLK inputs selected |
| 1 | LVCMOS_CLK input selected |



Table 3B. Clock Input Function Table

| | Inp | outs | | Outputs | | |
|---------|------------|----------------|----------------|---------|------------------------------|---------------|
| CLK_SEL | LVCMOS_CLK | CLK | nCLK | Q[0:11] | Input to Output Mode | Polarity |
| 0 | _ | 0 | 1 | LOW | Differential to Single-Ended | Non-Inverting |
| 0 | _ | 1 | 0 | HIGH | Differential to Single-Ended | Non-Inverting |
| 0 | _ | 0 | Biased; NOTE 1 | LOW | Single-Ended to Single-Ended | Non-Inverting |
| 0 | _ | 1 | Biased; NOTE 1 | HIGH | Single-Ended to Single-Ended | Non-Inverting |
| 0 | _ | Biased; NOTE 1 | 0 | HIGH | Single-Ended to Single-Ended | Inverting |
| 0 | _ | Biased; NOTE 1 | 1 | LOW | Single-Ended to Single-Ended | Inverting |
| 1 | 0 | _ | _ | LOW | Single-Ended to Single-Ended | Non-Inverting |
| 1 | 1 | _ | _ | HIGH | Single-Ended to Single-Ended | Non-Inverting |

NOTE 1: Please refer to the Application Information Section, Wiring the Differential Input to Accept Single-ended Levels.

Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics or AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

| Item | Rating |
|--|----------------------------------|
| Supply Voltage, V _{DD} | 4.6V |
| Inputs, V _I | -0.5V to V _{DD} + 0.5V |
| Outputs, V _O | -0.5V to V _{DDO} + 0.5V |
| Package Thermal Impedance, θ_{JA} | 73.6°C/W (0 mps) |
| Storage Temperature, T _{STG} | -65°C to 150°C |

DC Electrical Characteristics

Table 4A. Power Supply DC Characteristics, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$, $T_A = -40$ °C to 85°C

| 0 | D | T O | N4:: | Tourisani | NA! | 11 |
|-----------------|-----------------------|-----------------|---------|-----------|---------|-------|
| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
| V_{DD} | Power Supply Voltage | | 3.135 | 3.3 | 3.465 | V |
| V_{DDO} | Output Supply Voltage | | 3.135 | 3.3 | 3.465 | V |
| I _{DD} | Power Supply Current | | | | 55 | mA |

Table 4B. Power Supply DC Characteristics, $V_{DD} = V_{DDO} = 2.5V \pm 5\%$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------------|-------------------------|-----------------|---------|---------|---------|-------|
| V_{DD} | Positive Supply Voltage | | 2.375 | 2.5 | 2.625 | V |
| V_{DDO} | Output Supply Voltage | | 2.375 | 2.5 | 2.625 | V |
| I _{DD} | Power Supply Current | | | | 52 | mA |



Table 4C. Power Supply DC Characteristics, $V_{DD} = 3.3V \pm 5\%, \ V_{DDO} = 2.5V \pm 5\%, \ T_A = -40^{\circ}C$ to $85^{\circ}C$

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------------|-----------------------|-----------------|---------|---------|---------|-------|
| V_{DD} | Power Supply Voltage | | 3.135 | 3.3 | 3.465 | V |
| V_{DDO} | Output Supply Voltage | | 2.375 | 2.5 | 2.625 | V |
| I _{DD} | Power Supply Current | | | | 55 | mA |

Table 4D. DC Characteristics, $T_A = -40^{\circ}C$ to $85^{\circ}C$

| Symbol | Parameter | | Test Conditions | Minimum | Typical | Maximum | Units |
|------------------|--|----------|--|-----------|---------|------------------------|-------|
| V | Input High Voltage | LVCMOS | V _{DD} = 3.465V | 2 | | V _{DD} + 0.3 | V |
| V _{IH} | Input High Voltage | LVCMOS | V _{DD} = 2.625V | 1.7 | | V _{DD} + 0.3 | ٧ |
| V | Input Low Voltage | LVCMOS | V _{DD} = 3.465V | -0.3 | | 0.8 | ٧ |
| V_{IL} | input Low Voltage | LVCMOS | V _{DD} = 2.625V | -0.3 | | 0.7 | ٧ |
| I _{IN} | Input Current | • | $V_{IN} = V_{DD}$ or $V_{IN} = 3.465V$ or 2.625V | | | 300 | μA |
| W. | Output High Voltage; | NOTE 1 | $V_{DDO} = 3.3V \pm 5\%$ $I_{OH} = -24mA$ | 2.4 | | | V |
| V _{OH} | Output Flight Voltage, | NOTET | $V_{DDO} = 2.5V \pm 5\%$ $I_{OH} = -15mA$ | 1.8 | | | V |
| | | | $V_{DDO} = 3.3V \pm 5\%$ $I_{OL} = 24mA$ | | | 0.55 | V |
| V _{OL} | Output Low Voltage; | NOTE 1 | $V_{DDO} = 3.3V \pm 5\%$ $I_{OL} = 12mA$ | | | 0.30 | V |
| | | | $V_{DDO} = 2.5V \pm 5\%$ $I_{OL} = 15mA$ | | | 0.6 | V |
| V _{PP} | Peak-to-Peak Input Voltage; NOTE 2 | CLK/nCLK | V _{DD} = 3.465V or 2.625V | 0.15 | | 1.3 | V |
| V _{CMR} | Common Mode Input Voltage; NOTE 2, 3 | CLK/nCLK | V _{DD} = 3.465V or 2.625V | GND + 0.5 | | V _{DD} – 0.85 | V |

NOTE 1: Outputs capable of driving 50Ω transmission lines terminated with 50Ω to $V_{DDO}/2$. See Parameter Measurement section, *Output Load AC Test Circuit diagrams*.

NOTE 2: V_{IL} should not be less than -0.3V.

NOTE 3: Common mode voltage is defined as V_{IH} .



AC Electrical Characteristics

Table 5A. AC Characteristics, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$, $T_A = -40$ °C to 85°C

| Parameter | Symbol | | Test Conditions | Minimum | Typical | Maximum | Units |
|-------------------------------------|---------------------------------------|--|--|---------|---------|---------|-------|
| f _{MAX} | Output Frequency | | | | | 350 | MHz |
| | Propagation | CLK/nCLK; NOTE 1 | <i>f</i> ≤ 350MHz | 2 | | 4 | ns |
| t _{PD} | Propagation Delay | LVCMOS_CLK; NOTE 2 | <i>f</i> ≤ 350MHz | 2 | | 4 | ns |
| fjit | Buffer Additive F to Additive Phas | Phase Jitter, RMS; refer e Jitter Section | 155.52MHz, Integration Range: 12kHz – 20MHz | | 0.14 | 1 | ps |
| tsk(o) | Output Skew; No | OTE 3, 7 | Measured on the Rising Edge @ V _{DDO} /2 | | | 100 | ps |
| tsk(pp) | Part-to-Part Ske | w; NOTE 4, 7 | Measured on the Rising Edge @ V _{DDO} /2 | | | 1 | ns |
| t_R / t_F | Output Rise/Fall | Time | 0.8V to 2V | 0.2 | | 1.0 | ns |
| odc | Output Duty Cyc | ele | $f \le 150$ MHz, Ref = CLK/nCLK | 45 | 50 | 55 | % |
| t _{PZL} , t _{PZH} | Output Enable T | ime; NOTE 5 | | | | 5 | ns |
| t _{PLZ} , t _{PHZ} | Output Disable T | Γime; NOTE 5 | | | | 5 | ns |
| | Clock Enable | CLK_EN to CLK/nCLK | | 1 | | | ns |
| t _S | Setup Time; NOTE 6 | CLK_EN to LVCMOS_CLK | | 0 | | | ns |
| | Clock Enable | CLK/nCLK to CLK_EN | | 0 | | | ns |
| t _H | Hold Time; NOTE 6 | LVCMOS_CLK to CLK_EN | | 1 | | | ns |

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

- NOTE 1: Measured from the differential input crossing point to $V_{DDO}/2$ of the output.
- NOTE 2: Measured from $V_{DD}/2$ of the input to $V_{DDO}/2$ of the output.
- NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at $V_{DDO}/2$.
- NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltage and with equal load conditions. Using the same type of input on each device, the output is measured at $V_{DDO}/2$.
- NOTE 5: These parameters are guaranteed by characterization. Not tested in production.
- NOTE 6: Setup and Hold times are relative to the rising edge of the input clock.
- NOTE 7: This parameter is defined in accordance with JEDEC Standard 65.



Table 5B. AC Characteristics, $V_{DD} = V_{DDO} = 2.5V \pm 5\%$, $T_A = -40$ °C to 85°C

| Parameter | Symbol | | Test Conditions | Minimum | Typical | Maximum | Units |
|-------------------------------------|--|---|--|---------|---------|---------|-------|
| f _{MAX} | Output Frequence | у | | | | 350 | MHz |
| | Propagation | CLK/nCLK; NOTE 1 | <i>f</i> ≤ 350MHz | 1.5 | | 4.2 | ns |
| t _{PD} | Delay | LVCMOS_CLK; NOTE 2 | <i>f</i> ≤ 350MHz | 1.7 | | 4.4 | ns |
| <i>t</i> jit | Buffer Additive P to Additive Phase | hase Jitter, RMS; refer e Jitter Section | 155.52MHz, Integration Range: 12kHz – 20MHz | | 0.14 | 1 | ps |
| tsk(o) | Output Skew; NO | OTE 3, 7 | Measured on the Rising Edge @ V _{DDO} /2 | | | 160 | ps |
| tsk(pp) | Part-to-Part Skev | w; NOTE 4, 7 | Measured on the Rising Edge @ V _{DDO} /2 | | | 2 | ns |
| t_R / t_F | Output Rise/Fall | Time | 0.6V to 1.8V | 0.1 | | 1.0 | ns |
| odc | Output Duty Cyc | le | $f \le 150$ MHz, Ref = CLK/nCLK | 40 | | 60 | % |
| t _{PZL} , t _{PZH} | Output Enable Ti | ime; NOTE 5 | | | | 5 | ns |
| t _{PLZ} , t _{PHZ} | Output Disable T | ime; NOTE 5 | | | | 5 | ns |
| | Clock Enable | CLK_EN to CLK/nCLK | | 1 | | | ns |
| t _S | Setup Time; NOTE 6 | CLK_EN to LVCMOS_CLK | | 0 | | | ns |
| | Clock Enable | CLK/nCLK to CLK_EN | | 0 | | | ns |
| t _H | Hold Time; NOTE 6 | LVCMOS_CLK to CLK_EN | | 1 | | | ns |

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

- NOTE 1: Measured from the differential input crossing point to $V_{DDO}/2$ of the output.
- NOTE 2: Measured from $V_{DD}/2$ of the input to $V_{DDO}/2$ of the output.
- NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at V_{DDO}/2.
- NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltage and with equal load conditions. Using the same type of input on each device, the output is measured at $V_{DDO}/2$.
- NOTE 5: These parameters are guaranteed by characterization. Not tested in production.
- NOTE 6: Setup and Hold times are relative to the rising edge of the input clock.
- NOTE 7: This parameter is defined in accordance with JEDEC Standard 65.



Table 5C. AC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $V_{DDO} = 2.5V \pm 5\%$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

| Parameter | Symbol | | Test Conditions | Minimum | Typical | Maximum | Units |
|-------------------------------------|--|---|--|---------|---------|---------|-------|
| f _{MAX} | Output Frequence | у | | | | 350 | MHz |
| | Propagation | CLK/nCLK; NOTE 1 | <i>f</i> ≤ 350MHz | 2 | | 4 | ns |
| t _{PD} | Delay | LVCMOS_CLK; NOTE 2 | <i>f</i> ≤ 350MHz | 2 | | 4 | ns |
| fjit | Buffer Additive P to Additive Phase | hase Jitter, RMS; refer e Jitter Section | 155.52MHz, Integration Range: 12kHz – 20MHz | | 0.14 | 1 | ps |
| tsk(o) | Output Skew; NO | OTE 3, 7 | Measured on the Rising Edge @ V _{DDO} /2 | | | 100 | ps |
| tsk(pp) | Part-to-Part Skev | w; NOTE 4, 7 | Measured on the Rising Edge @ V _{DDO} /2 | | | 1 | ns |
| t_R / t_F | Output Rise/Fall | Time | 0.8V to 2V | 0.1 | | 1.0 | ns |
| odc | Output Duty Cyc | le | $f \le 200$ MHz, Ref = CLK/nCLK | 45 | | 55 | % |
| t _{PZL} , t _{PZH} | Output Enable Ti | ime; NOTE 5 | | | | 5 | ns |
| t _{PLZ} , t _{PHZ} | Output Disable T | ime; NOTE 5 | | | | 5 | ns |
| | Clock Enable | CLK_EN to CLK/nCLK | | 1 | | | ns |
| t _S | Setup Time; NOTE 6 | CLK_EN to LVCMOS_CLK | | 0 | | | ns |
| | Clock Enable | CLK/nCLK to CLK_EN | | 0 | | | ns |
| t _H | Hold Time; NOTE 6 | LVCMOS_CLK to CLK_EN | | 1 | | | ns |

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

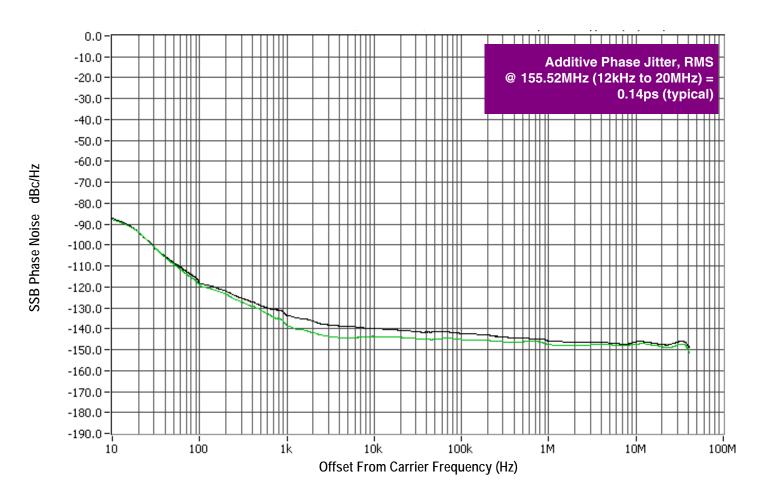
- NOTE 1: Measured from the differential input crossing point to $V_{DDO}/2$ of the output.
- NOTE 2: Measured from $V_{DD}/2$ of the input to $V_{DDO}/2$ of the output.
- NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at V_{DDO}/2.
- NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltage and with equal load conditions. Using the same type of input on each device, the output is measured at $V_{DDO}/2$.
- NOTE 5: These parameters are guaranteed by characterization. Not tested in production.
- NOTE 6: Setup and Hold times are relative to the rising edge of the input clock.
- NOTE 7: This parameter is defined in accordance with JEDEC Standard 65.



Additive Phase Jitter

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the *dBc Phase Noise*. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio of the power in the 1Hz band to the power in the

fundamental. When the required offset is specified, the phase noise is called a *dBc* value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.

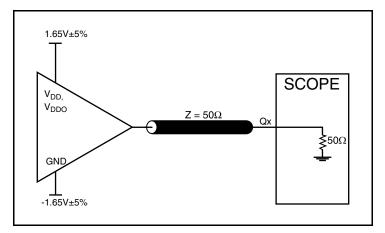


As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the device.

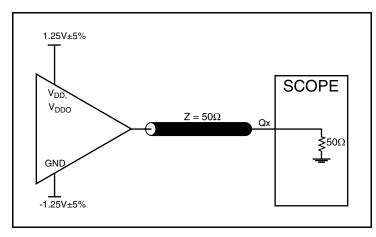
This is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.



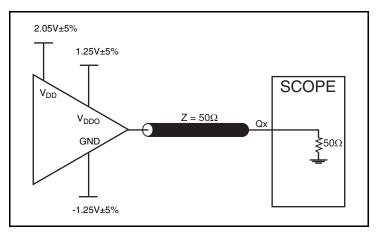
Parameter Measurement Information



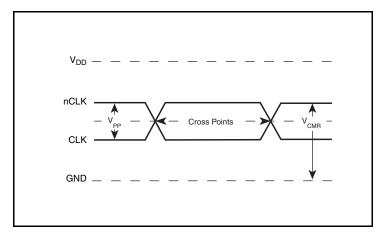
3.3V Core/3.3V LVCMOS Output Load AC Test Circuit



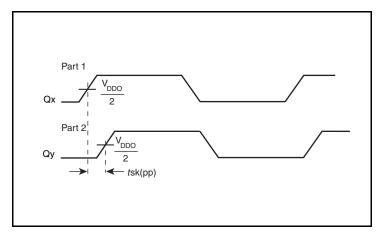
2.5V Core/2.5V LVCMOS Output Load AC Test Circuit



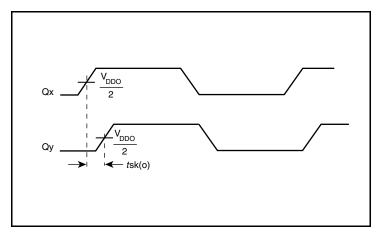
3.3V Core/2.5V LVCMOS Output Load AC Test Circuit



Differential Input Level



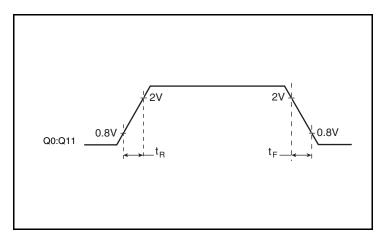
Part-to-Part Skew

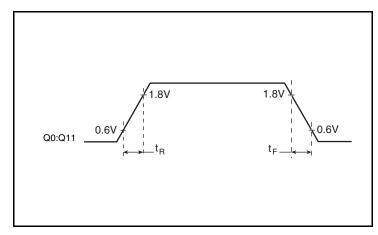


Output Skew

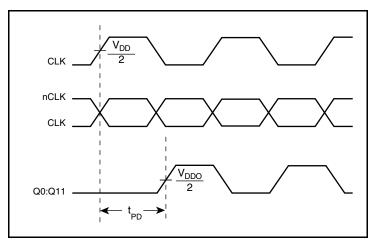


Parameter Measurement Information, continued

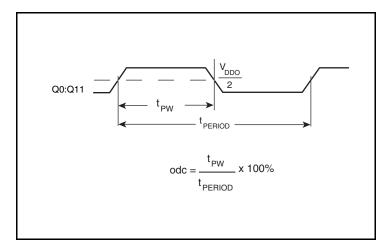




3.3V Output Rise/Fall Time



2.5V Output Rise/Fall Time



Propagation Delay

Output Duty Cycle/Pulse Width/Period



Application Information

Wiring the Differential Input to Accept Single Ended Levels

Figure 1 shows how the differential input can be wired to accept single ended levels. The reference voltage V_REF = $V_{DD}/2$ is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio of R1 and R2 might need to be adjusted to position the V_REF in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and $V_{DD} = 3.3V$, V_REF should be 1.25V and R2/R1 = 0.609.

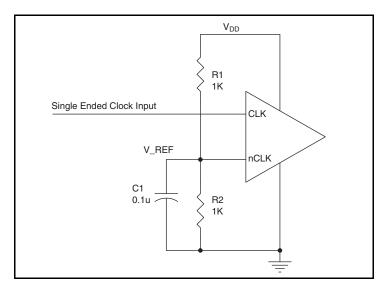


Figure 1. Single-Ended Signal Driving Differential Input

Recommendations for Unused Input and Output Pins

Inputs:

CLK/nCLK Inputs

For applications not requiring the use of the differential input, both CLK and nCLK can be left floating. Though not required, but for additional protection, a $1k\Omega$ resistor can be tied from CLK to ground.

CLK Input

For applications not requiring the use of a clock input, it can be left floating. Though not required, but for additional protection, a $1k\Omega$ resistor can be tied from the CLK input to ground.

LVCMOS Control Pins

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A $1k\Omega$ resistor can be used.

Outputs:

LVCMOS Outputs

All unused LVCMOS output can be left floating. There should be no trace attached.



Differential Clock Input Interface

The CLK/nCLK accepts LVDS, LVPECL, LVHSTL, SSTL, HCSL and other differential signals. Both signals must meet the V_{PP} and V_{CMR} input requirements. Figures 2A to 2F show interface examples for the CLK/nCLK input driven by the most common driver types. The input interfaces suggested here are examples only. Please consult with the

vendor of the driver component to confirm the driver termination requirements. For example, in Figure 2A, the input termination applies for IDT open emitter LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.

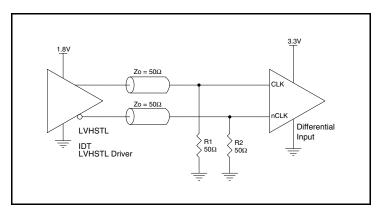


Figure 2A. CLK/nCLK Input Driven by an IDT Open Emitter LVHSTL Driver

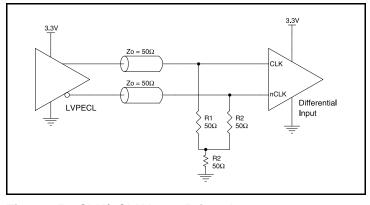


Figure 2B. CLK/nCLK Input Driven by a 3.3V LVPECL Driver

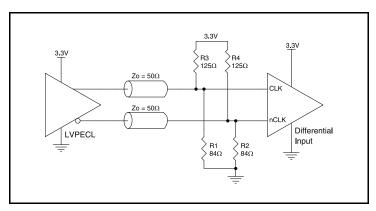


Figure 2C. CLK/nCLK Input Driven by a 3.3V LVPECL Driver

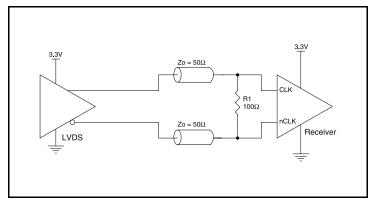


Figure 2D. CLK/nCLK Input Driven by a 3.3V LVDS Driver

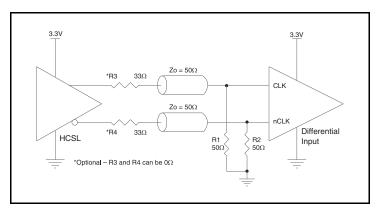


Figure 2E. CLK/nCLK Input Driven by a 3.3V HCSL Driver

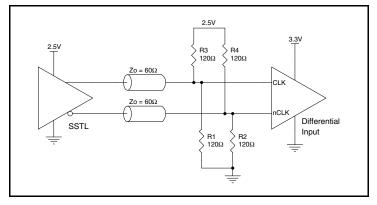


Figure 2F. CLK/nCLK Input Driven by a 2.5V SSTL Driver



Reliability Information

Table 6. $\theta_{\mbox{\scriptsize JA}}$ vs. Air Flow Table for a 32-Lead LQFP

| $	heta_{\sf JA}$ vs. Air Flow | | | | |
|---|----------|----------|----------|--|
| Meters per Second | 0 | 1 | 2.5 | |
| Multi-Layer PCB, JEDEC Standard Test Boards | 73.6°C/W | 63.9°C/W | 60.3°C/W | |

Transistor Count

The transistor count for 83948I-147 is: 1040 Pin compatible with the MPC9448



Package Outline and Package Dimension

Package Outline - Y Suffix for 32-Lead LQFP

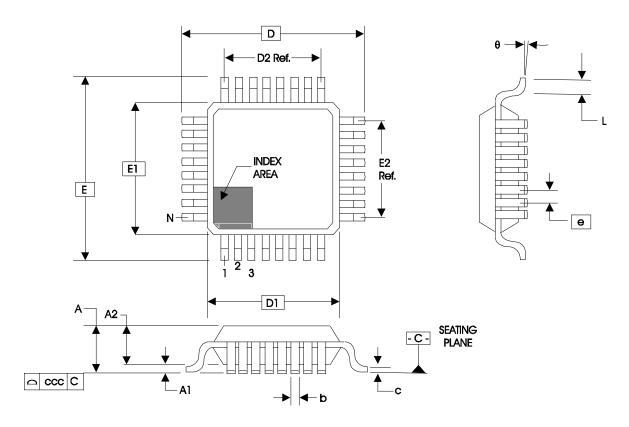


Table 7. Package Dimensions for 32-Lead LQFP

| JEDEC Variation: ABC - HD All Dimensions in Millimeters | | | | | |
|---|-------------------------|------|------|--|--|
| Symbol | Minimum Nominal Maximum | | | | |
| N | 32 | | | | |
| Α | 1.60 | | | | |
| A1 | 0.05 0.10 0.15 | | | | |
| A2 | 1.35 1.40 1.45 | | | | |
| b | 0.30 | 0.37 | 0.45 | | |
| С | 0.09 | | 0.20 | | |
| D&E | 9.00 Basic | | | | |
| D1 & E1 | 7.00 Basic | | | | |
| D2 & E2 | 5.60 Ref. | | | | |
| е | 0.80 Basic | | | | |
| L | 0.45 | 0.60 | 0.75 | | |
| θ | 0° | | 7° | | |
| ccc | 0.10 | | | | |

Reference Document: JEDEC Publication 95, MS-026



Ordering Information

Table 8. Ordering Information

| Part/Order Number | Marking | Package | Shipping Packaging | Temperature |
|-------------------|--------------|--------------------------|--------------------|---------------|
| 83948AYI-147LF | ICS948AI147L | "Lead-Free" 32-Lead LQFP | Tray | -40°C to 85°C |
| 83948AYI-147LFT | ICS948AI147L | "Lead-Free" 32-Lead LQFP | Tape & Reel | -40°C to 85°C |



Revision History Sheet

| Rev | Table | Page | Description of Change | Date |
|-----|------------------|------------------------------|---|----------|
| В | T2 | 1 2 7 | Features Section - added Lead-Free bullet. Pin Characteristics Table - changed C_{IN} from 4pF max. to 4pF typical; and added 5Ω min. and 12Ω max to R_{OUT} . Updated Single Ended Signal Driving Differential Input diagram. | 11/21/05 |
| | Т8 | 10 | Added Recommendations for Unused Input and Output Pins. Ordering Information Table - added lead-free part number, marking, and note. | |
| С | T5A T5B T6 | 1 5 6 7 11 12 | Features Section - added Additive Phase Jitter bullet. 3.3V AC Characteristics Table - added Additive Phase Jitter. 3.3V AC Characteristics Table - added Additive Phase Jitter. Added Additive Phase Jitter section. Updated Differential Input Clock Interface section. Updated Reliability Information. Updated format throughout the datasheet. | 1/15/08 |
| D | T4C T5C | 1 4 7 9 | Features Section - added mix voltage to supply voltage bullet. Added Mix DC Characteristics Power Supply Table. Added Mix AC Characteristics Table. Parameter Measurement Information Section - added 3.3V/2.5V LVCMOS Output Load AC Test Circuit diagram. Ordering Information Table - deleted ICS prefix from Part/Order Number column. | 4/1/09 |
| D | T1 | 2 | Output supply pins, Changed V _{DD} to V _{DDO} | 11/1/12 |
| D | Т8 | 15 | Removed leaded orderable parts from Ordering Information table | 11/14/12 |
| D | Т8 | 15 17 | Fixed typo: removed extra "I" from orderable part number. Updated Headers and Footers. Updated Contact information. | 7/17/14 |
| D | | | Removed ICS from part number where needed. Updated data sheet header and footer. | 3/30/16 |



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